

[Error Analysis and Retention-Aware Error Management for NAND Flash Memory](#)

Authors: [Cai, Yu](#) / [Yalcin, Gulay](#) / [Mutlu, Onur](#) / [Haratsch, Eric](#) / [Cristal, Adrián](#) / [Unsal, Osman](#) / [Mai, Ken](#)

Publication: Intel Technology Journal

Volume / Number / Pagination: 17 / 1 / 140?164

Barcelona Supercomputing Center - Centro Nacional de Supercomputación

Source URL (retrieved on 20 Jun 2021 - 21:45): <https://www.bsc.es/es/node/40563>